

4-Mbit (512 K × 8) Static RAM

Features

- Higher speed up to 55 ns
- Wide voltage range: 2.2 V to 3.6 V and 4.5 V to 5.5 V
- Ultra low standby power
 Typical standby current: 1 µA
 Maximum standby current: 7 µA
- Ultra low active power
 Typical active current: 2 mA at f = 1 MHz
- **Easy** memory expansion with \overline{CE} and \overline{OE} features
- Automatic power-down when deselected
- Complementary metal oxide semiconductor (CMOS) for optimum speed and power
- Available in Pb-free 32-Pin shrunk thin small outline package (STSOP) package

Functional Description

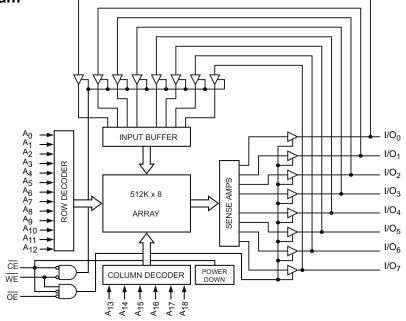
The CY62148ESL is a high performance CMOS static RAM organized as 512 K words by 8-bits. This device features advanced circuit design to provide ultra low active current. This is ideal for providing More Battery LifeTM (MoBL[®]) in portable applications such as cellular telephones. The device also has an automatic power-down feature that significantly reduces power consumption. Placing the device in standby mode reduces power consumption by more than 99 percent when deselected (CE HIGH). The eight input and output pins (I/O₀ through I/O₇) are placed in a high impedance state when the device is deselected (CE HIGH), the outputs are disabled (OE HIGH), or during a write operation (CE LOW and WE LOW).

To write to the device, take Chip Enable (\overline{CE}) and Write Enable (\overline{WE}) inputs LOW. Data on the eight I/O pins (I/O₀ through I/O₇) is then written into the location specified on the address pins (A₀ through A₁₈).

To read <u>from</u> the device, take Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins appear on the I/O pins.

For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines.

Logic Block Diagram



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Pin Configuration

	Figure 1. 32-Pin STSOP (Top View)	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	STSOP Top View (not to scale)	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

Product Portfolio

Product	Range	V _{CC} Range (V) ^[1]		Power Dissipation					
			Speed (ns)	Operating I _{CC} , (mA)			Standby, I _{SB2}		
				f = 1 MHz		f = f _{max}		(µÅ)	
				Typ ^[2]	Max	Typ ^[2]	Max	Typ ^[2]	Max
CY62148ESL	Industrial/ Automotive-A	2.2 V to 3.6 V and 4.5 V to 5.5 V	55	2	2.5	15	20	1	7

Notes

1. Datasheet specifications are not guaranteed for V_{CC} in the range of 3.6 V to 4.5 V. 2. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, $T_A = 25$ °C.





Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage temperature65 °C to +150 °C
Ambient temperature with power applied55 °C to +125 °C
Supply voltage to ground potential0.5 V to 6.0 V
DC voltage applied to outputs in high Z state ^[3, 4] 0.5 V to 6.0 V
DC input voltage ^[3, 4] 0.5 V to 6.0 V
Output current into outputs (low)20 mA
Static discharge voltage
Latch-up current>200 mA

Operating Range

Device	Range	Ambient Temperature	V_{CC^[5]}
CY62148ESL	Industrial/ Automotive-A	–40 °C to +85 °C	2.2 V to 3.6 V, and 4.5 V to 5.5 V

Electrical Characteristics

Over the operating range

Parameter Description		Teet	Conditions	55 ns (In	dustrial/A	utomotive-A)	Unit
Parameter	Description	lest	Conditions	Min	Typ ^[6]	Мах	Unit
V _{OH}	Output HIGH voltage	2.2 <u><</u> V _{CC} ≤ 2.7	I _{OH} = -0.1 mA	2.0	-	-	V
		2.7 <u><</u> V _{CC} <u><</u> 3.6	I _{OH} = -1.0 mA	2.4	-	-	
		4.5 <u><</u> V _{CC} <u><</u> 5.5	I _{OH} = -1.0 mA	2.4	-	-	
V _{OL}	Output LOW voltage	2.2 <u>≤</u> V _{CC} <u>≤</u> 2.7	I _{OL} = 0.1 mA	-	-	0.4	V
		2.7 <u><</u> V _{CC} <u><</u> 3.6	I _{OL} = 2.1 mA	-	-	0.4	
		4.5 <u><</u> V _{CC} <u><</u> 5.5	I _{OL} = 2.1 mA	-	-	0.4	
V _{IH}	Input HIGH voltage	2.2 <u>≤</u> V _{CC} <u>≤</u> 2.7		1.8	-	V _{CC} + 0.3	V
		2.7 <u><</u> V _{CC} <u><</u> 3.6			-	V _{CC} + 0.3	
		4.5 <u><</u> V _{CC} <u><</u> 5.5			-	V _{CC} + 0.5	
V _{IL} ^[7]	Input LOW voltage	$2.2 \le V_{CC} \le 2.7$		-0.3	-	0.4	V
		2.7 <u><</u> V _{CC} <u><</u> 3.6		-0.3	-	0.6	
		4.5 <u><</u> V _{CC} <u><</u> 5.5		-0.5	-	0.6	
I _{IX}	Input leakage current	$GND \leq V_I \leq V_{CC}$		-1	-	+1	μA
I _{OZ}	Output leakage current	$GND \leq V_O \leq V_{CC}$, output	disabled	-1	-	+1	μA
I _{CC}	V _{CC} operating supply	$f = f_{max} = 1/t_{RC}$	$V_{CC} = V_{CCmax}$	_	15	20	mA
	current	f = 1 MHz	I _{OUT} = 0 mA, CMOS levels	-	2	2.5	
I _{SB1} ^[8]	Automatic CE	$\overline{CE} \ge V_{CC} - 0.2 \text{ V}, \text{ V}_{IN} \ge$	$V_{\rm CC}$ – 0.2 V or V _{IN} \leq 0.2 V,	-	1	7	μA
	power-down current — CMOS inputs	$f = f_{max}$ (address and dates) $V_{CC} = V_{CC(max)}$	ata only), $f = 0$ (\overline{OE} and \overline{WE}),	-			
I _{SB2} ^[8]	Automatic CE power-down current — CMOS inputs	$\overline{CE} \ge V_{CC} - 0.2 \text{ V}, \text{ V}_{IN} \ge$	$V_{\rm CC}$ – 0.2 V or V _{IN} \leq 0.2 V,	-	1	7	μA

Notes

3. $V_{IL}(min) = -2.0$ V for pulse durations less than 20 ns.

V_{IL}(min) = -2.0 V for pulse durations less than 20 ns.
 V_{IL}(max) = V_{CC} + 0.75 V for pulse durations less than 20 ns.
 Full device AC operation assumes a minimum of 100 µs ramp time from 0 to V_{CC} (min) and 200 µs wait time after V_{CC} stabilization.
 Typical values are included for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC}(typ), T_A = 25 °C.
 Under DC conditions the device meets a V_{IL} of 0.8 V (for V_{CC} range of 2.7 V to 3.6 V and 4.5 V to 5.5 V) and 0.6 V (for V_{CC} range of 2.2 V to 2.7 V). However, in dynamic conditions Input LOW voltage applied to the device must not be higher than 0.6 V and 0.4 V for the above ranges. Refer to AN13470 for details.

8. Chip enable (CE) must be HIGH at CMOS level to meet the I_{SB1} / I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.



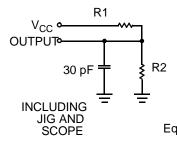
Capacitance

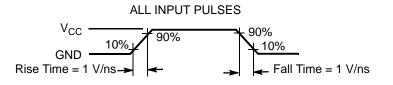
Parameter ^[9]	Description	Test Conditions	Max	Unit
C _{IN}	Input capacitance	$T_{A} = 25 ^{\circ}C, f = 1 \text{MHz},$	10	pF
C _{OUT}	Output capacitance	$V_{CC} = V_{CC}(Typ)$	10	pF

Thermal Resistance

Parameter ^[9]	Description	Test Conditions	STSOP	Unit
Θ_{JA}	Thermal resistance (junction to ambient)	Still air, soldered on a 3×4.5 inch, two-layer printed circuit board	49.02	°C/W
Θ ^{JC}	Thermal resistance (junction to case)		14.07	°C/W

Figure 2. AC Test Loads and Waveforms





Equivalent to: THEVENIN EQUIVALENT

R_{TH} OUTPUT • V

Parameter	2.5 V	3.0 V	5.0 V	Unit
R1	16667	1103	1800	Ω
R2	15385	1554	990	Ω
R _{TH}	8000	645	639	Ω
V _{TH}	1.20	1.75	1.77	V

9. Tested initially and after any design or process changes that may affect these parameters.

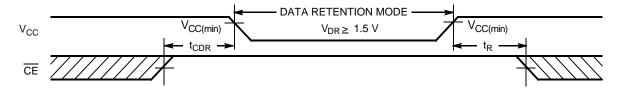


Data Retention Characteristics

Over the operating range

Parameter	Description	Conditions		Min	Typ ^[10]	Max	Unit
V _{DR}	V _{CC} for data retention			1.5	-	-	V
I _{CCDR} ^[11]	Data retention current	$\label{eq:cell} \begin{split} \overline{CE} \geq V_{CC} &= 0.2 \text{ V}, \text{V}_{\text{IN}} \geq V_{CC} &= 0.2 \text{ V} \text{ or } \\ \text{V}_{\text{IN}} \leq 0.2 \text{ V}, \text{V}_{CC} &= 1.5 \text{ V} \end{split}$	Industrial/ Automotive-A	-	1	7	μA
t _{CDR}	Chip deselect to data retention time			0	-	-	ns
t _R ^[12]	Operation recovery time			55	-	_	ns

Figure 3. Data Retention Waveform



Notes

10. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, $T_A = 25 \text{ °C}$. 11. Chip enable (CE) must be HIGH at CMOS level to meet the $I_{SB1} / I_{SB2} / I_{CCDR}$ spec. Other inputs can be left floating. 12. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \ge 100 \,\mu s$ or stable at $V_{CC(min)} \ge 100 \,\mu s$.



Switching Characteristics

Over the operating range

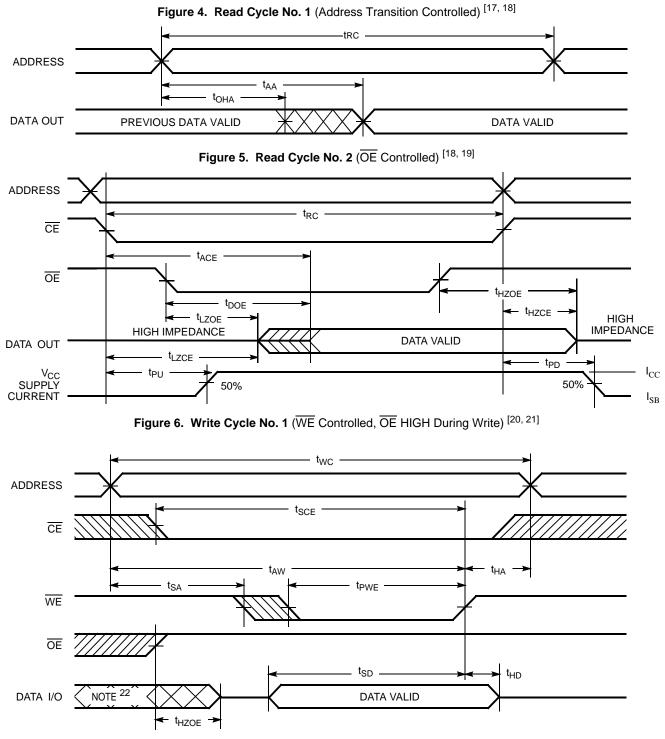
Parameter ^[13]	Description	55 ns (Industria	al/Automotive-A)	Unit	
Parameter [10]	Description	Min	Max		
Read Cycle		·			
t _{RC}	Read cycle time	55	-	ns	
t _{AA}	Address to data valid	-	55	ns	
t _{OHA}	Data hold from address change	10	-	ns	
t _{ACE}	CE LOW to data valid	-	55	ns	
t _{DOE}	OE LOW to data valid	-	25	ns	
t _{LZOE}	OE LOW to low Z ^[14]	5	-	ns	
t _{HZOE}	OE HIGH to high Z ^[14, 15]	-	20	ns	
t _{LZCE}	CE LOW to low Z ^[14]	10	_	ns	
t _{HZCE}	CE HIGH to high Z ^[14, 15]	-	20	ns	
t _{PU}	CE LOW to power-up	0	-	ns	
t _{PD}	CE HIGH to power-up	-	55	ns	
Write Cycle [16]	·				
t _{WC}	Write cycle time	55	-	ns	
t _{SCE}	CE LOW to write end	40	-	ns	
t _{AW}	Address setup to write end	40	-	ns	
t _{HA}	Address hold from write end	0	-	ns	
t _{SA}	Address setup to write start	0	_	ns	
t _{PWE}	WE pulse width	40	-	ns	
t _{SD}	Data setup to write end	25	-	ns	
t _{HD}	Data hold from write end	0	-	ns	
t _{HZWE}	WE LOW to high Z ^[14, 15]	-	20	ns	
t _{LZWE}	WE HIGH to low Z ^[14]	10	-	ns	

Notes

<sup>Notes
13. Test conditions for all parameters other than tri-state parameters assume signal transition time of 3 ns or less (1 V/ns), timing reference levels of V_{CC(typ)}/2, input pulse levels of 0 to V_{CC(typ)}, and output loading of the specified I_{OL}/I_{OH} as shown in AC Test Loads and Waveforms on page 5.
14. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} for any device.
15. t_{HZOE}, t_{HZCE}, and t_{HZWE} transitions are measured when the output enter a high impedance state.
16. The internal write time of the memory is defined by the overlap of WE, CE = V_{IL}. All signals must be ACTIVE to initiate a write and any of these signals can terminate a write by going INACTIVE. The data input setup and hold timing must be referenced to the edge of the signal that terminates the write.</sup>



Switching Waveforms



Notes

- 17. <u>Dev</u>ice is continuously selected. \overline{OE} , $\overline{CE} = V_{IL}$.
- 18. WE is HIGH for read cycles.
- 19. Address valid before or similar to CE transition LOW.
- 20. Data I/O is high impedance if $\overline{OE} = V_{1H.}$ 21. If CE goes HIGH simultaneously with WE HIGH, the output remains in high impedance state. 22. During this period, the I/Os are in output state. Do not apply input signals.



Switching Waveforms (continued)

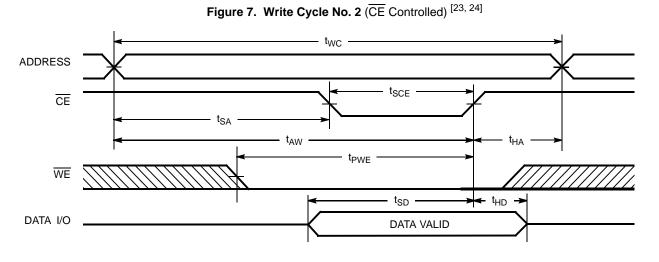
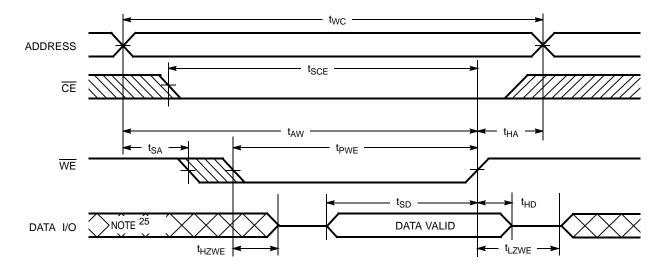


Figure 8. Write Cycle No. 3 (WE Controlled, OE LOW) [24]



Truth Table

CE	WE	OE	I/O	Mode	Power
H ^[26]	Х	Х	High Z	Deselect/power-down	Standby (I _{SB})
L	Н	L	Data out	Read	Active (I _{CC})
L	Н	Н	High Z	Output disabled	Active (I _{CC})
L	L	Х	Data in	Write	Active (I _{CC})

Notes

<sup>Notes
23. Data I/O is high impedance if OE = V_{IH}.
24. If CE goes HIGH simultaneously with WE HIGH, the output remains in high impedance state.
25. During this period, the I/Os are in output state. Do not apply input signals.
26. Chip enable (CE) must be HIGH at CMOS level to meet the I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.</sup>





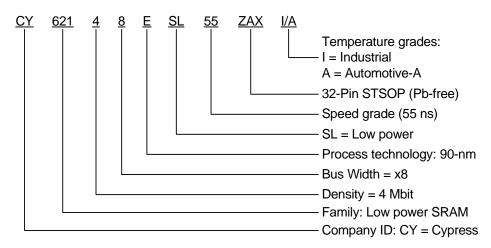
Ordering Information

Table 1 lists the CY62148ESL MoBL key package features and ordering codes. The table contains only the parts that are currently available. If you do not see what you are looking for, contact your local sales representative. For more information, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products.

Table 1.	Key features and	d Ordering Information	ı
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Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
55	CY62148ESL-55ZAXI	51-85094	32-Pin STSOP (Pb-free)	Industrial
	CY62148ESL-55ZAXA	51-85094	32-Pin STSOP (Pb-free)	Automotive-A

Ordering Code Definitions





Package Diagram

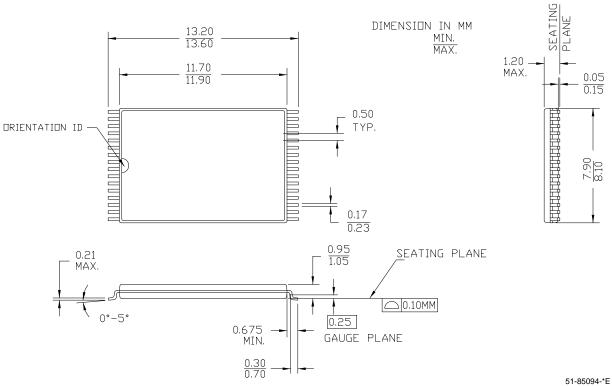


Figure 9. 32-Pin Shrunk Thin Small Outline Package (8 mm × 13.4 mm), 51-85094

Acronyms

Acronym	Description
CMOS	complementary metal oxide semiconductor
I/O	input/output
MoBL	more battery life
SRAM	static random access memory
STSOP	shrunk thin small outline package

Document Conventions

Units of Measure

Symbol	Unit of Measure	
ns	nano seconds	
V	volts	
μA	micro amperes	
mA	milli amperes	
pF	pico Farad	
°C	degree Celsius	
W	watts	





Document History Page

Document Title: CY62148ESL MoBL[®] 4-Mbit (512 K × 8) Static RAM Document Number: 001-50045

Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	2612938	VKN/PYRS	01/21/09	New datasheet
*A	2800124	VKN	11/06/2009	Included Automotive-A information
*B	2947039	VKN	06/10/2010	Added footnote related to chip enable in Truth Table Added footnote for the I _{SB2} parameter in Electrical Characteristics Updated Package Diagram Updated links in Sales, Solutions, and Legal Information
*C	3006318	AJU	08/23/10	Template update. Updated table of contents. Added acronyms, units of measure and ordering code definitions. Added reference to note 8 to parameter I _{SB1} on page 4 under Electrical characterisitics table. Added reference to note 11 to parameter I _{CCDR} on page 6 under data retention characteristics table.



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Revised August 23, 2010

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